In the United States Patent and Trademark Office

Information Disclosure Statement

Commissioner of Patents and Trademarks
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.

Following are comments on these references pursuant to Rule 98:

PATENTS

Patents which describe ellipsometric monitoring of thin films are:

        Patent No. 6,573,999 to Yang;
        Patent No. 6,349,594 to Yabe;
        Patent No. 5,486,701 to Norton et al.;
        Patent No. 5,798,837 to Aspnes et al.;
        Patent No. 4,105,338 to Kuroha;
        Patent No. 5,181,080 to Fanton et al.;
        Patent No. 4,826,321 to Coates et al.;
        Patent No. 5,910,842 to Piwonka-Corle et al.;
        Patent No. 5,517,312 to Finarov;

        Patent No. 6,278,519 to Rosenscwaig et al.;
        Patent No. 4,899,055 to Adams;
        Patent No. 5,798,837 to Aspnes et al.;
        Patent No. 5,793,480 to Lacey et al.;
        Patent No. 5,900,939 to Aspnes et al.;
        Patent No. 5,595,916 to Fujimura et al.;
        Patent No. 6,605,482 to Celii et al.; and

        Patent Application No. US 2002/0176081 A1.

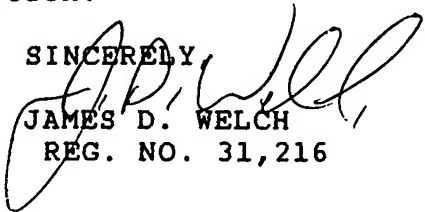Patents which discuss monitoring wittness samples are:

        Patent No. 6,278,809 to Johnson et al.;

Patent No. 5,871,805 to Lemelson;

SCIENTIFIC PAPER

A relevant Scientific Paper is titled "Data Analysis for Spectroscopic Ellipsometry", Thin SOlid Films, 234 (1993) is disclosed as it defines parameters N = Cos(2); C = Sin(2)Cos( ) and S = Sin(2)Sin ( ) which are applied in the prefered embodiment of the disclosed invnetion.

SINCERELY,

JAMES D. WELCH
REG. NO. 31,216

Form PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
LIST OF PRIOR ART CITED BY APPLICANT *(Use sev ral sheets if necessary)*		APPLICANT Jehr a Tiwald	
		FILING DATE	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6573999	6/2003	Yang.	356	632	
	AB	6349594	2/2002	Yabe	73	150	
	AC	5484701	1/1996	Norton et al.	250	372	
	AD	5798837	8/1998	Aspnes et al	356	369	
	AE	4105338	8/1978	Kuroha	356	118	
	AF	5181080	1/1993	Fanton et al	356	369	
	AG	4826321	5/1989	Coates et al.	356	351	
	AH	5910842	6/1999	Piwonka-Corle et al	356	369	
	AI	5517312	5/1996	Finarov	356	386	
	AJ	6278519	8/2001	Rosencwaig et al	356	369	
	AK	4899055	2/1990	Adams	250	372	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	Opsal et al Pub No US 2002/0156081 A1, Nov. 28, 2002, Serial No. 10/178,984
	AS	

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5798837	8/1998	Aspnes et al.	356	369	
	AB	5793480	8/1998	Lacey et al.	356	73	
	AC	5900939	5/1999	Aspnes et al	356	369	
	AD	5595916	1/1997	Fujimura et al	437	8	
	AE	6605482	8/2003	Celii et al.	438	16	
	AF	6278809	8/2001	Johnson et al	385	17	
	AG	5871805	2/1999	Lemelson	427	8	
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	AL							
	AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	Data Analysis for Spectroscopic Ellipsometry, Thin Solid Films 234 (1993) by Jellison Jr.
	AS	

| EXAMINER | DATE CONSIDERED |
| | |

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